



Dual P-Channel Enhancement Mode Field Effect Transistor

● **Features**

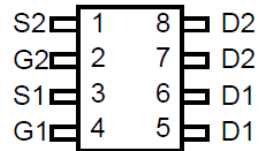
V_{DS} (V) = -30V

I_D = -8A (V_{GS} = -10V)

$R_{DS(ON)}$ < 19m Ω (V_{GS} = -10V)

$R_{DS(ON)}$ < 25m Ω (V_{GS} = -4.5V)

● **Pin Configurations**

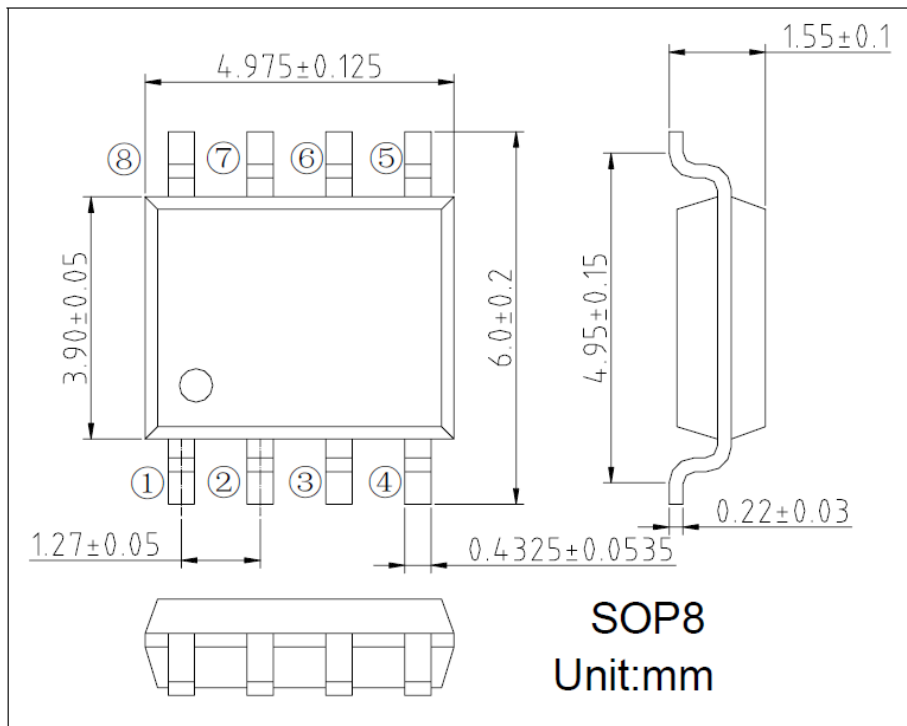


● **General Description**

The HX4805 uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge.

This device is suitable for use as a load switch or in PWM applications. Standard Product HX4805 is Pb-free.

● **Package Information**



● **Absolute Maximum Ratings @ $T_A=25^\circ\text{C}$ unless otherwise noted**

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DSS}	-30	V
Gate-Source Voltage		V_{GSS}	± 20	V
Drain Current (Continuous) *AC	$T_A=25^\circ\text{C}$	I_D	-8	A
	$T_A=70^\circ\text{C}$		-6.4	



Drain Current (Pulse) *B		I_{DM}	-40	A
Power Dissipation	$T_A=25^{\circ}\text{C}$	P_D	2	W
	$T_A=70^{\circ}\text{C}$		1.5	
Operating Temperature/ Storage Temperature		T_{JJ}/T_{STG}	-55~150	$^{\circ}\text{C}$

● **Electrical Characteristics** @ $T_A=25^{\circ}\text{C}$ unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250 \mu A$	-30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30V, V_{GS} = 0V$	--	--	-1	μA
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{DS} = -250 \mu A$	-1.2	-1.4	-2	V
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -8A$	--	16	19	m Ω
		$V_{GS} = -4.5V, I_D = -5A$	--	18.5	25	m Ω
Forward Transconductance	g_{FS}	$V_{DS} = -5V, I_D = -8A$	--	21.7	--	S
Diode Forward Voltage	V_{SD}	$I_{SD} = -1A, V_{GS} = 0V$	--	-0.7	-1.0	V
Maximum Body-Diode Continuous Current	I_S		--	--	2.6	A
Switching						
Total Gate Charge	Q_g	$V_{GS} = -10V, V_{DS} = -15V, I_D = -8A$	--	33.82	43.97	nC
Gate-Source Charge	Q_{gs}		--	4.93	6.41	nC
Gate-Drain Charge	Q_{gd}		--	5.2	6.76	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{GS} = -10V, V_{DS} = -15V, R_L = 15\Omega, R_{GEN} = 6\Omega$	--	15.44	30.88	ns
Turn-on Rise Time	t_r		--	5.04	10.08	ns
Turn-off Delay Time	$t_{d(off)}$		--	71.04	142.08	ns
Turn-off Fall Time	t_f		--	16.8	33.6	ns
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -15V, f = 1\text{MHz}$	--	1973	2200	pF
Output Capacitance	C_{oss}		--	491	--	pF
Reverse Transfer Capacitance	C_{rss}		--	231	325	pF

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the $\leq 10\text{s}$ junction to ambient thermal resistance rating.



● TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

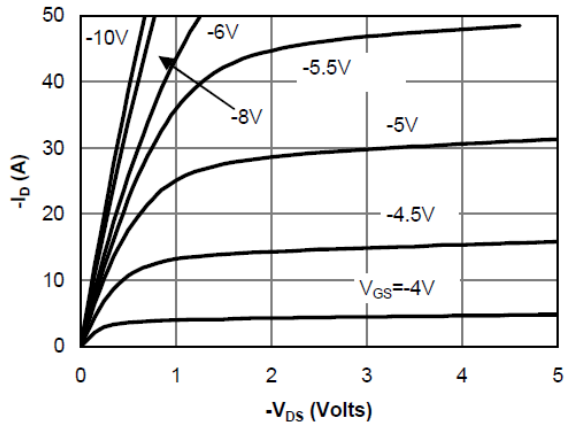


Fig 1: On-Region Characteristics

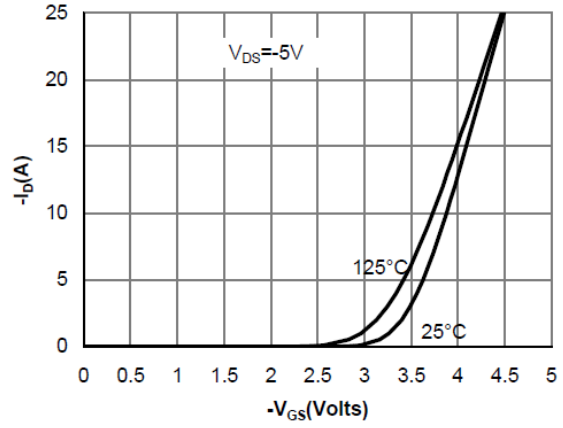


Figure 2: Transfer Characteristics

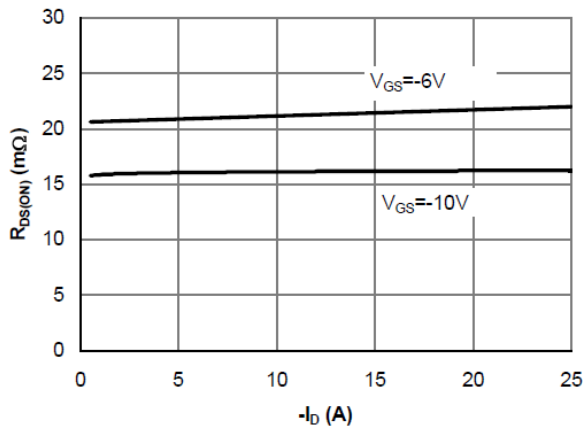


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

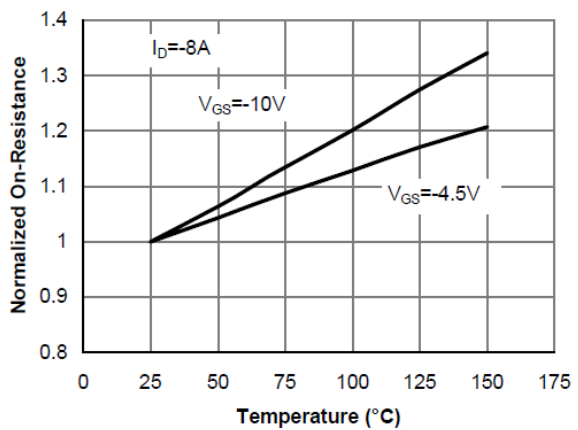


Figure 4: On-Resistance vs. Junction Temperature

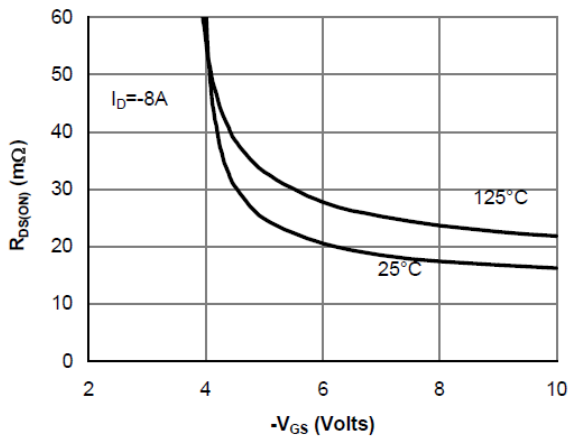


Figure 5: On-Resistance vs. Gate-Source Voltage

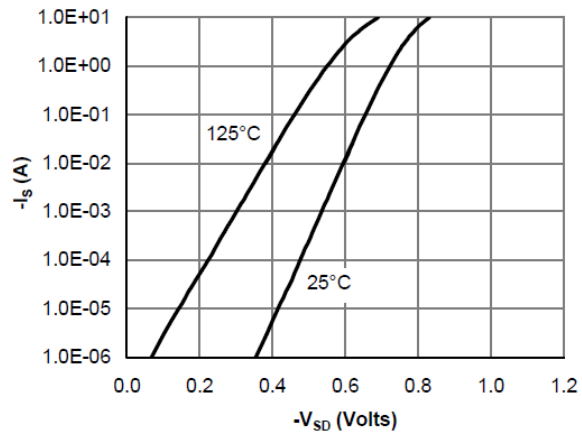


Figure 6: Body-Diode Characteristics

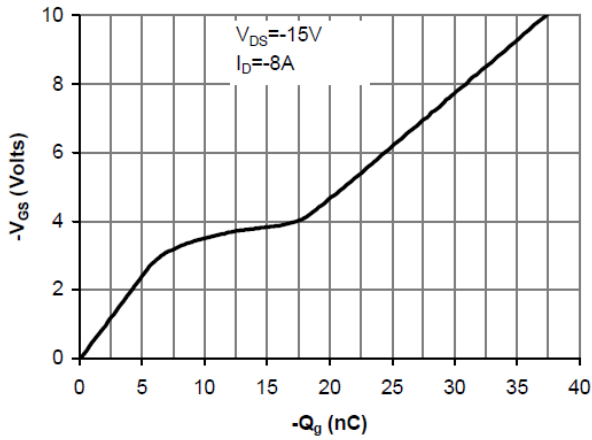


Figure 7: Gate-Charge Characteristics

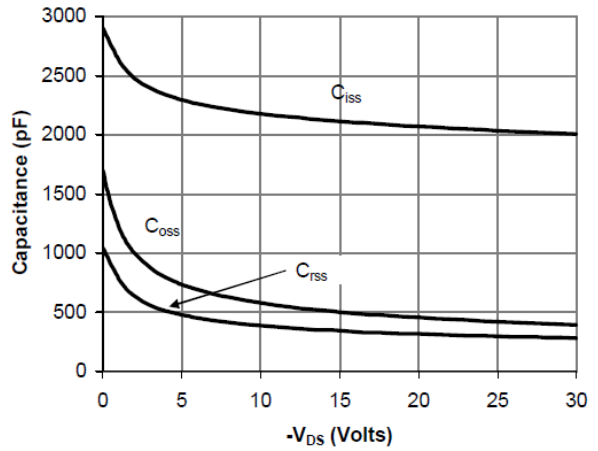


Figure 8: Capacitance Characteristics

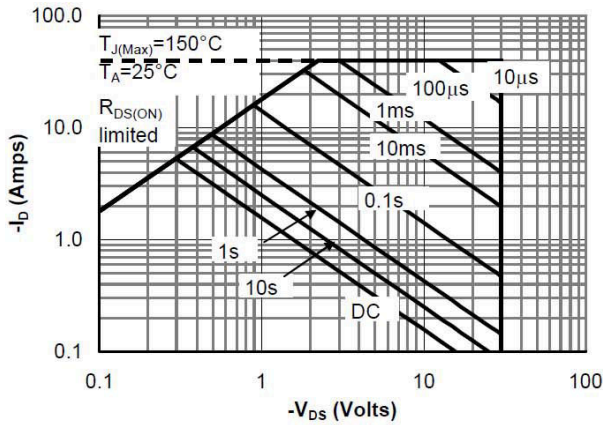


Figure 9: Maximum Forward Biased Safe Operating Area

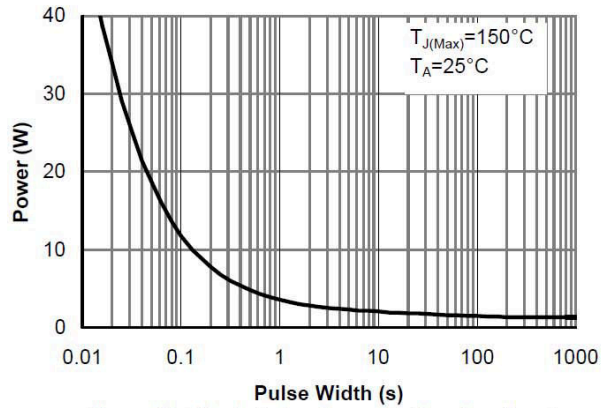


Figure 10: Single Pulse Power Rating Junction-to-Ambient

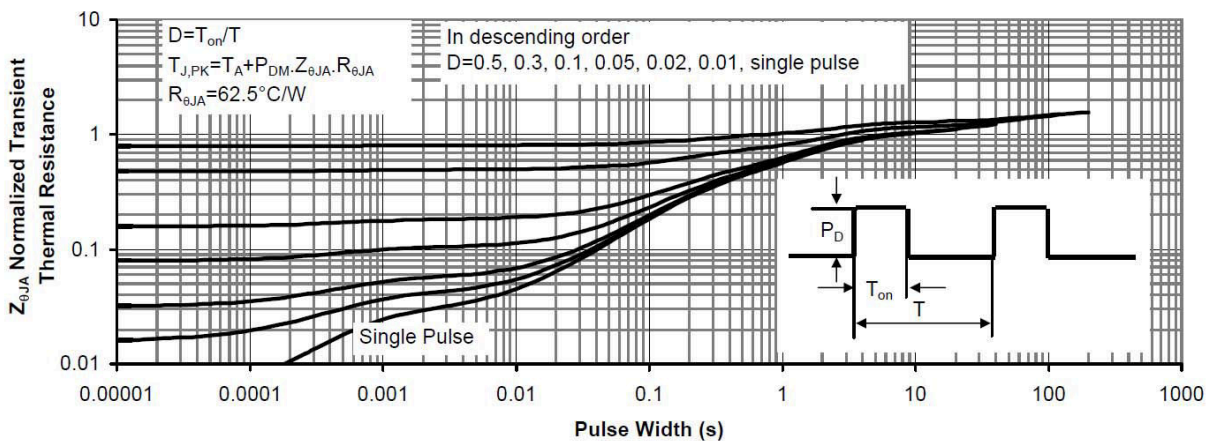


Figure 11: Normalized Maximum Transient Thermal Impedance



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